

Features

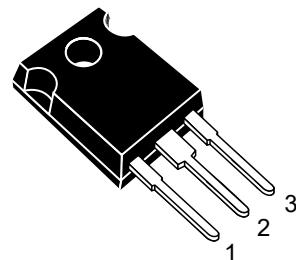
- 3rd generation SiC MOSFET technology
- High blocking voltage with low on-resistance
- High-speed switching with low capacitances
- Fast intrinsic diode with low reverse recovery (Q_{rr})
- Halogen free, RoHS compliant

V_{DS}	%\$V
I_{D(Tc=25°C)}	115A
R_{DS(on)}	16mΩ

Benefits

- Reduce switching losses and minimize gate ringing
- Higher system efficiency
- Reduce cooling requirements
- Increase power density
- Increase system switching frequency

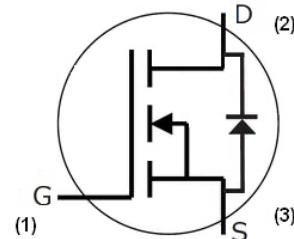
Package TO-247-3L



Applications

- Solar inverters
- EV motor drive
- High voltage DC/DC converters
- Switched mode power supplies
- Load switch

Equivalent Circuit



Maximum Ratings ($T_C = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Value	Unit	Test Conditions	Note
$V_{DS\max}$	Drain - Source Voltage	1200	V	$V_{GS} = 0 \text{ V}$, $I_D = 100 \mu\text{A}$	
$V_{GS\max}$	Gate - Source Voltage (dynamic)	-8/+19	V	AC ($f > 1 \text{ Hz}$)	Note 1
V_{GSop}	Gate - Source Voltage (static)	-4/+15	V	Static	Note 2
I_D	Continuous Drain Current	115	A	$V_{GS} = 15 \text{ V}$, $T_c = 25^\circ\text{C}$	Fig. 19
		85		$V_{GS} = 15 \text{ V}$, $T_c = 100^\circ\text{C}$	
$I_{D(\text{pulse})}$	Pulsed Drain Current	250	A	Pulse width t_p limited by $T_{j\max}$	
P_D	Power Dissipation	556	W	$T_c = 25^\circ\text{C}$, $T_j = 175^\circ\text{C}$	Fig. 20
T_J , T_{stg}	Operating Junction and Storage Temperature	-40 to +175	°C		
T_L	Solder Temperature	260	°C	1.6mm (0.063") from case for 10s	
M_d	Mounting Torque	1 8.8	Nm lbf-in	M3 or 6-32 screw	

Note (1): When using MOSFET Body Diode $V_{GS\max} = -4\text{V}/+19\text{V}$

Note (2): MOSFET can also safely operate at 0/+15 V

Electrical Characteristics (T_C = 25°C unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max	Unit	Test Conditions	Note
V _{(BR)DSS}	Drain-Source Breakdown Voltage	1200			V	V _{GS} = 0 V, I _D = 100 μA	
V _{GS(th)}	Gate Threshold Voltage	1.8	2.5	3.6	V	V _{DS} = V _{GS} , I _D = 23 mA	Fig. 11
			2.0		V	V _{DS} = V _{GS} , I _D = 23 mA, T _J = 175°C	
I _{DSS}	Zero Gate Voltage Drain Current		1	50	μA	V _{DS} = 1200 V, V _{GS} = 0 V	
I _{GSS}	Gate-Source Leakage Current		10	250	nA	V _{GS} = 15 V, V _{DS} = 0 V	
R _{DS(on)}	Drain-Source On-State Resistance	11.2	16	22.3	mΩ	V _{GS} = 15 V, I _D = 75 A	Fig. 4, 5, 6
			28.8			V _{GS} = 15 V, I _D = 75 A, T _J = 175°C	
g _{fs}	Transconductance		53		S	V _{DS} = 20 V, I _{DS} = 75 A	Fig. 7
			47			V _{DS} = 20 V, I _{DS} = 75 A, T _J = 175°C	
C _{iss}	Input Capacitance		6085		pF	V _{GS} = 0 V, V _{DS} = 1000 V f = 100 KHz V _{AC} = 25 mV	Fig. 17, 18
C _{oss}	Output Capacitance		230				
C _{rss}	Reverse Transfer Capacitance		13				
E _{oss}	C _{oss} Stored Energy		130		μJ		Fig. 16
E _{ON}	Turn-On Switching Energy (SiC Diode FWD)		4.64		mJ	V _{DS} = 800 V, V _{GS} = -4 V/+15 V, I _D = 75 A, R _{G(ext)} = 5Ω, L = 65.7 μH, T _J = 175°C	Fig. 26
E _{OFF}	Turn Off Switching Energy (SiC Diode FWD)		2.93				
E _{ON}	Turn-On Switching Energy (Body Diode FWD)		7.79		mJ	V _{DS} = 800 V, V _{GS} = -4 V/+15 V, I _D = 75 A, R _{G(ext)} = 5Ω, L = 65.7 μH, T _J = 175°C	Fig. 26
E _{OFF}	Turn Off Switching Energy (Body Diode FWD)		2.95				
t _{d(on)}	Turn-On Delay Time		174		ns	V _{DD} = 800 V, V _{GS} = -4 V/15 V R _{G(ext)} = 5 Ω, I _D = 75 A, L = 65.7 μH Timing relative to V _{DS} , Inductive load	Fig. 27
t _r	Rise Time		28				
t _{d(off)}	Turn-Off Delay Time		84				
t _f	Fall Time		27				
R _{G(int)}	Internal Gate Resistance		2.6		Ω	f = 1 MHz, V _{AC} = 25 mV	
Q _{gs}	Gate to Source Charge		70		nC	V _{DS} = 800 V, V _{GS} = -4 V/15 V I _D = 75 A Per IEC60747-8-4 pg 21	Fig. 12
Q _{gd}	Gate to Drain Charge		60				
Q _g	Total Gate Charge		207				



MDDG2C120R016K3

1200V N-Channel SiC Power MOSFET

Reverse Diode Characteristics ($T_C = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Typ.	Max.	Unit	Test Conditions	Note
V_{SD}	Diode Forward Voltage	4.6		V	$V_{GS} = -4 \text{ V}, I_{SD} = 37.5 \text{ A}, T_J = 25^\circ\text{C}$	Fig. 8, 9, 10
		4.2		V	$V_{GS} = -4 \text{ V}, I_{SD} = 37.5 \text{ A}, T_J = 175^\circ\text{C}$	
I_S	Continuous Diode Forward Current		112	A	$V_{GS} = -4 \text{ V}, T_C = 25^\circ\text{C}$	Note 1
$I_{S,pulse}$	Diode pulse Current		250	A	$V_{GS} = -4 \text{ V}$, pulse width t_p limited by T_{Jmax}	Note 1
t_{rr}	Reverse Recover time	96		ns	$V_{GS} = -4 \text{ V}, I_{SD} = 75 \text{ A}, V_R = 800 \text{ V}$ $\text{dif/dt} = 900 \text{ A}/\mu\text{s}, T_J = 175^\circ\text{C}$	Note 1
Q_{rr}	Reverse Recovery Charge	604		nC		
I_{rrm}	Peak Reverse Recovery Current	15		A	$V_{GS} = -4 \text{ V}, I_{SD} = 75 \text{ A}, V_R = 800 \text{ V}$ $\text{dif/dt} = 1400 \text{ A}/\mu\text{s}, T_J = 175^\circ\text{C}$	Note 1
t_{rr}	Reverse Recover time	58		ns		
Q_{rr}	Reverse Recovery Charge	672		nC		
I_{rrm}	Peak Reverse Recovery Current	22		A		

Thermal Characteristics

Symbol	Parameter	Typ.	Unit	Test Conditions	Note
$R_{\theta JC}$	Thermal Resistance from Junction to Case	0.27	°C/W		Fig. 21
$R_{\theta JA}$	Thermal Resistance From Junction to Ambient	40			

Typical Performance

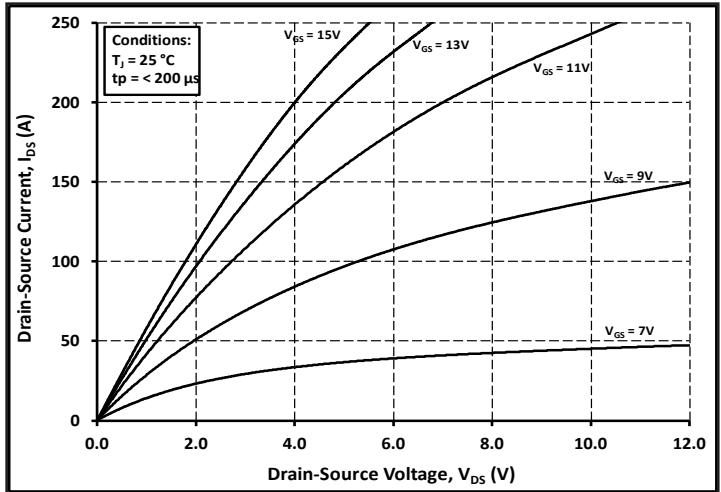
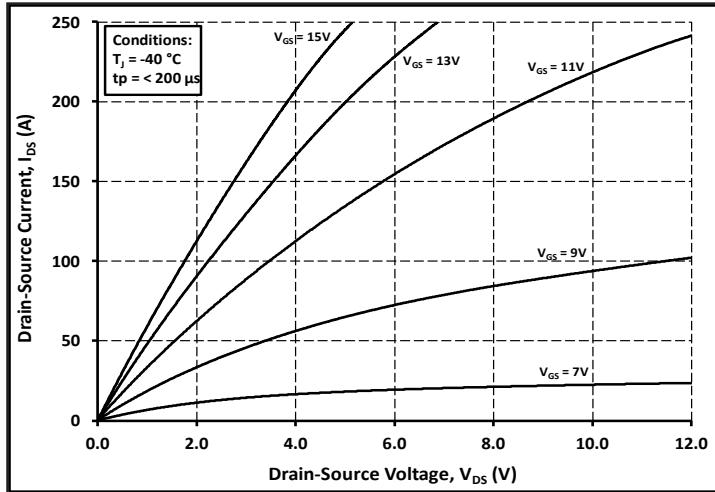


Figure 1. Output Characteristics $T_J = -40^\circ\text{C}$

Figure 2. Output Characteristics $T_J = 25^\circ\text{C}$

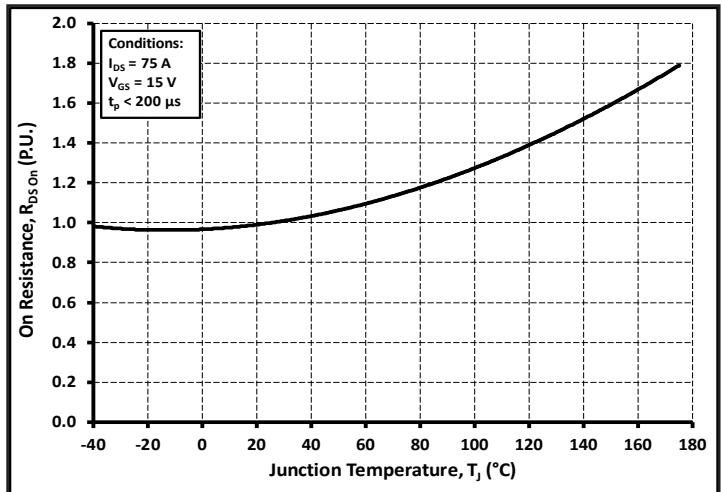
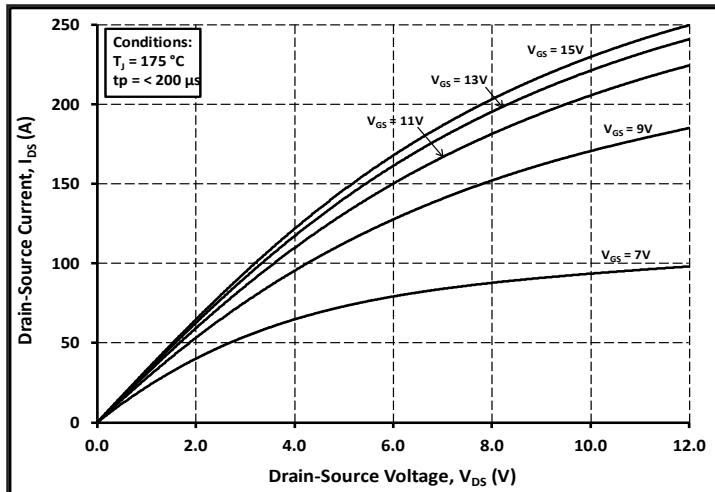


Figure 3. Output Characteristics $T_J = 175^\circ\text{C}$

Figure 4. Normalized On-Resistance vs. Temperature

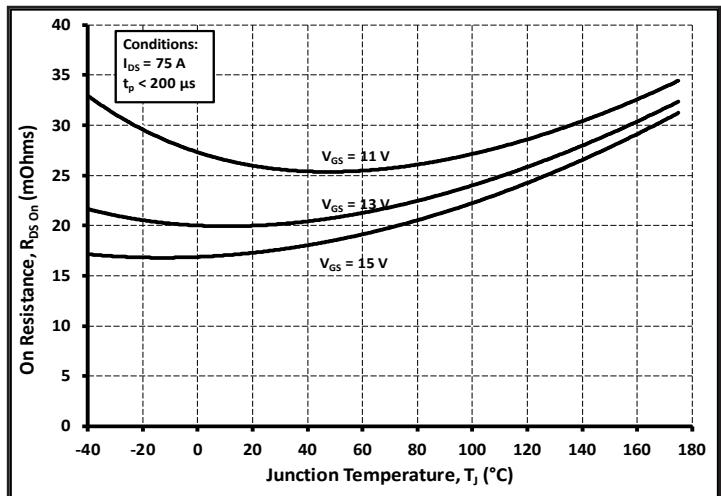
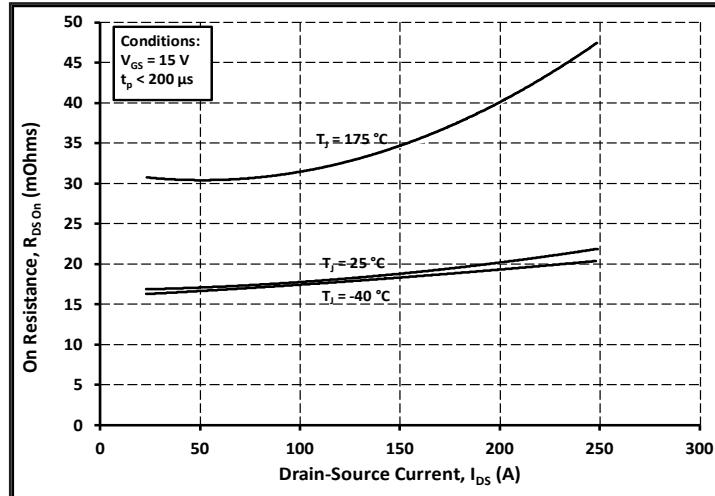
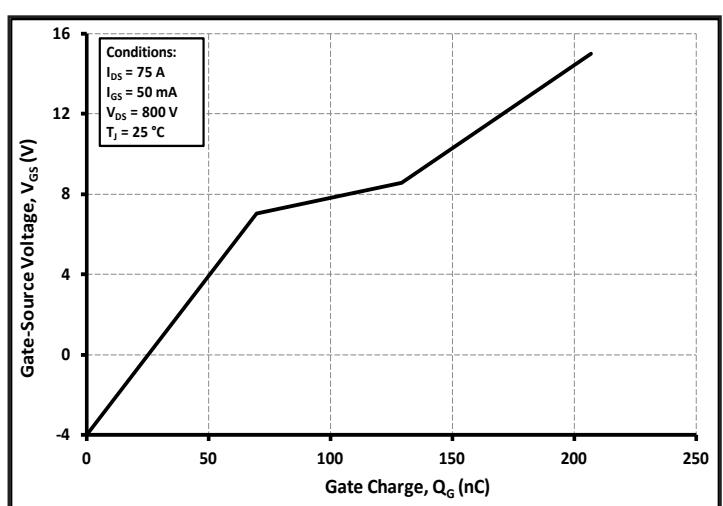
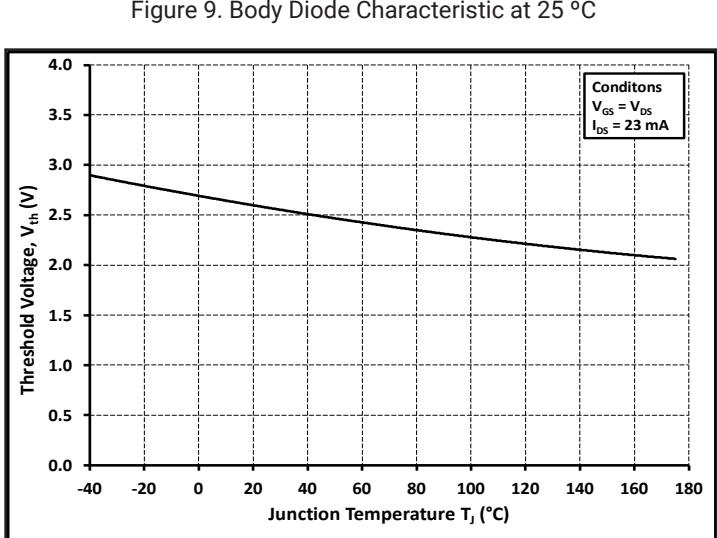
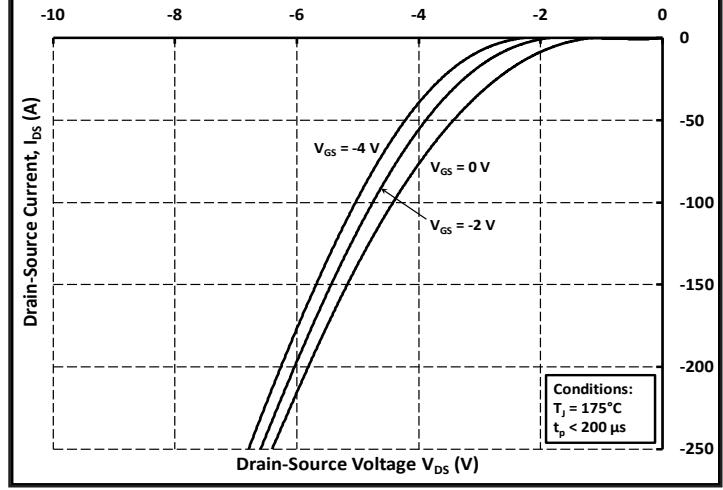
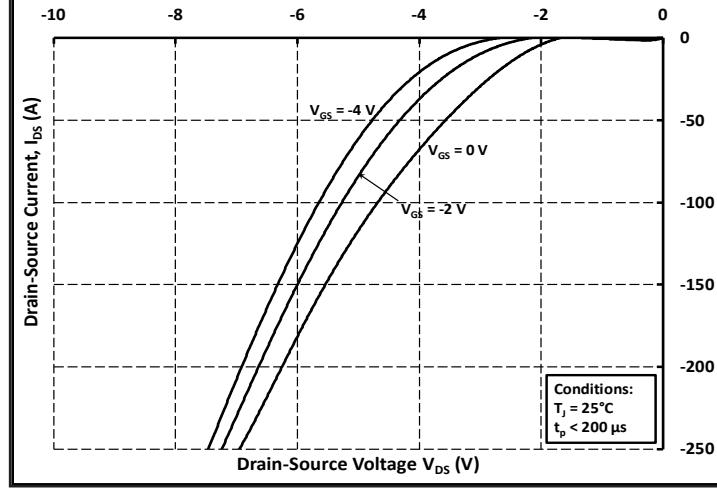
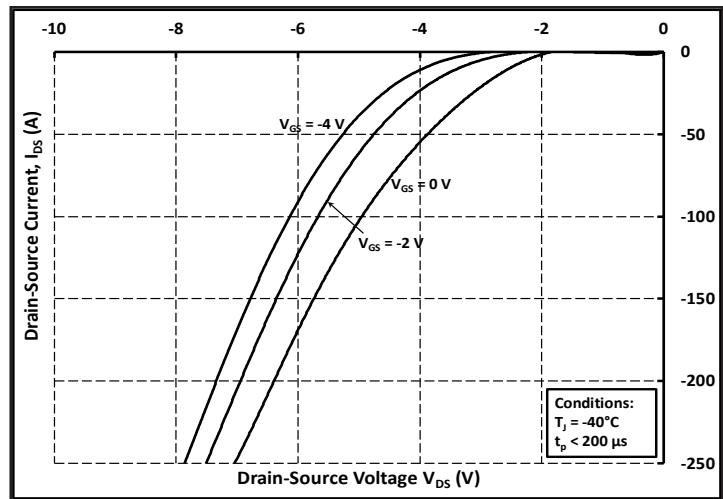
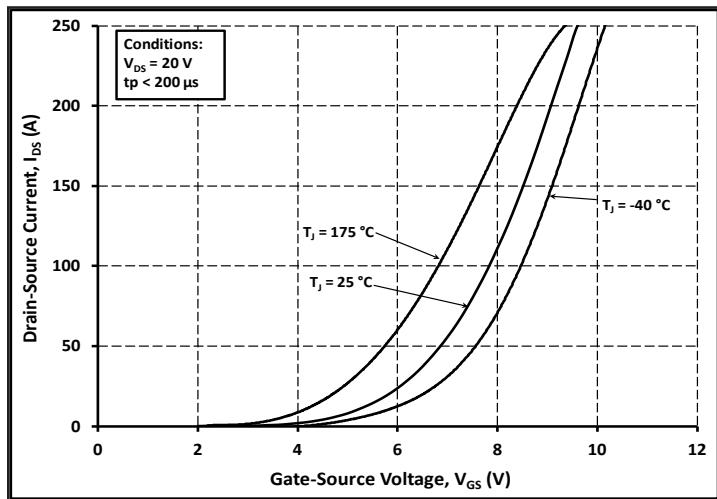


Figure 5. On-Resistance vs. Drain Current
For Various Temperatures

Figure 6. On-Resistance vs. Temperature
For Various Gate Voltage



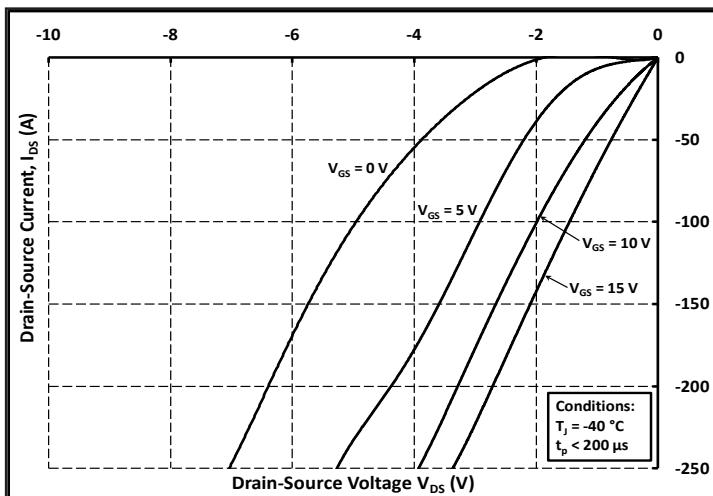
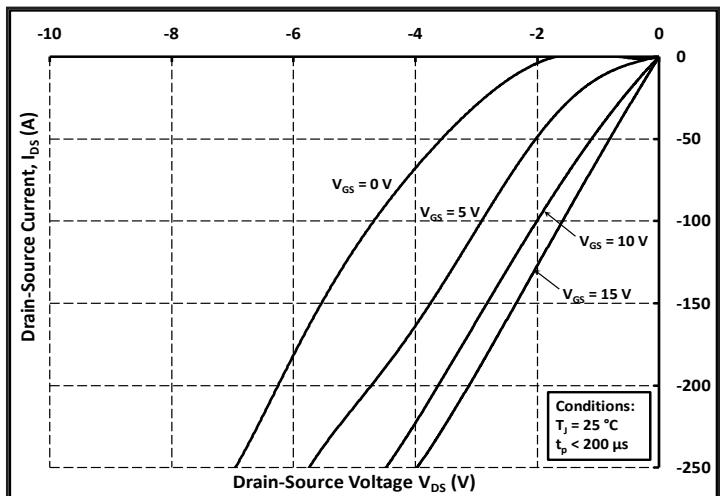
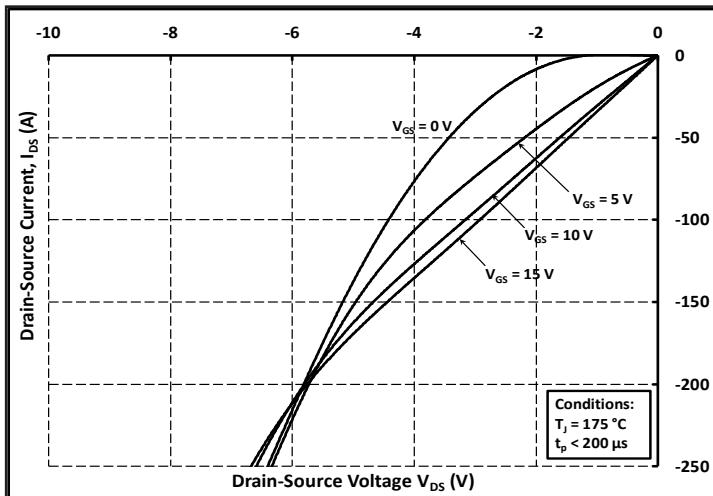
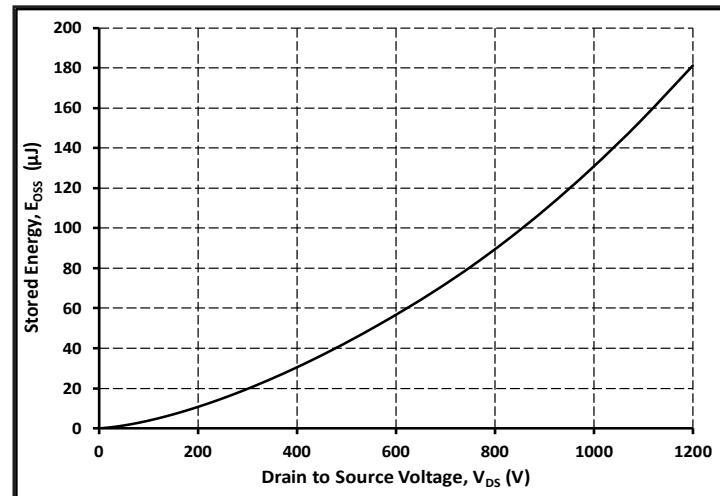

 Figure 13. 3rd Quadrant Characteristic at $-40 \text{ }^\circ\text{C}$

 Figure 14. 3rd Quadrant Characteristic at $25 \text{ }^\circ\text{C}$

 Figure 15. 3rd Quadrant Characteristic at $175 \text{ }^\circ\text{C}$


Figure 16. Output Capacitor Stored Energy

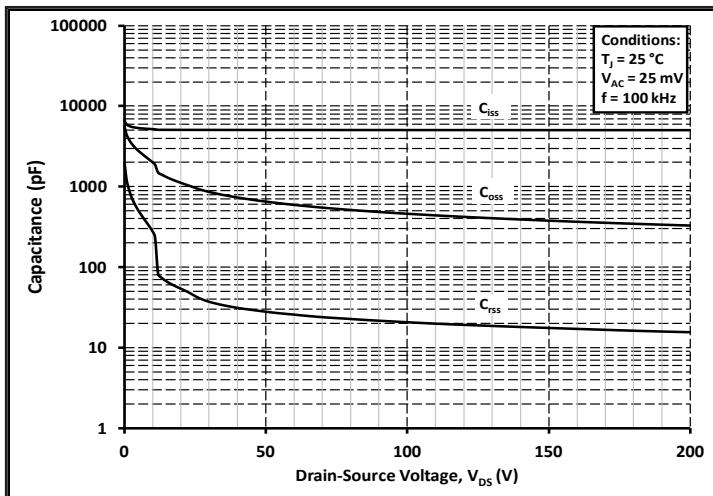


Figure 17. Capacitances vs. Drain-Source Voltage (0 - 200V)

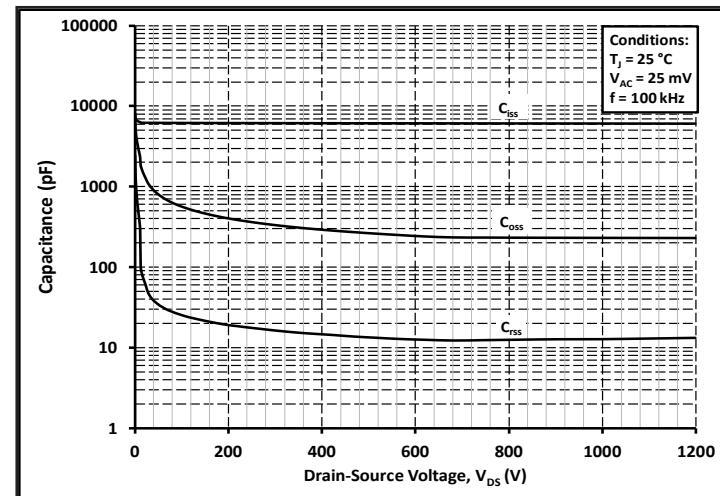


Figure 18. Capacitances vs. Drain-Source Voltage (0 - 1200V)

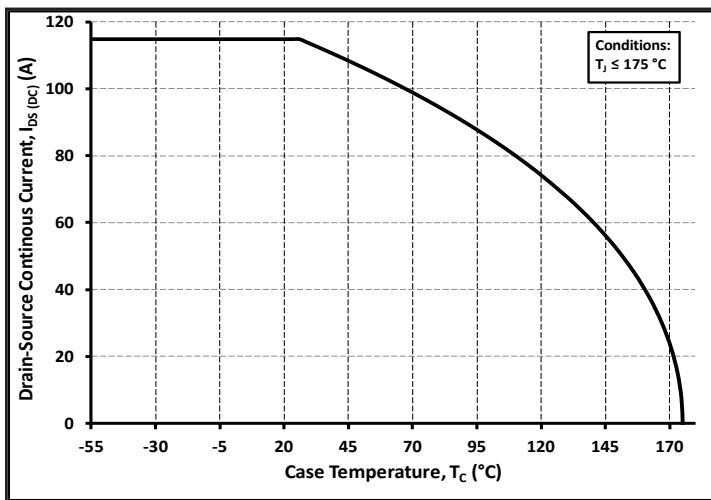


Figure 19. Continuous Drain Current Derating vs.
Case Temperature

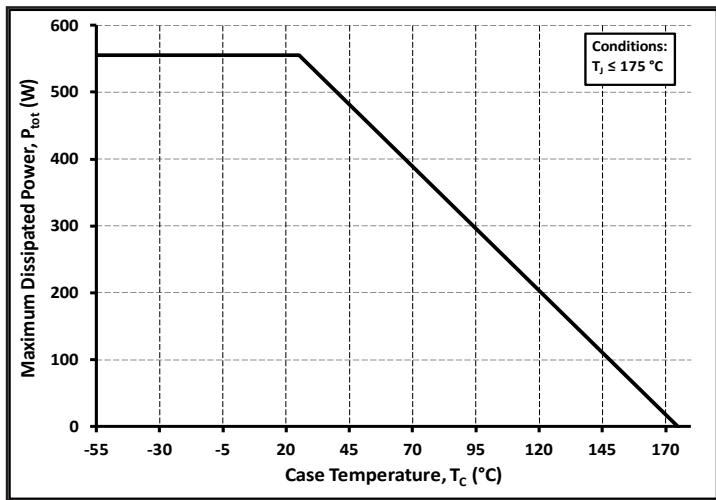


Figure 20. Maximum Power Dissipation Derating vs.
Case Temperature

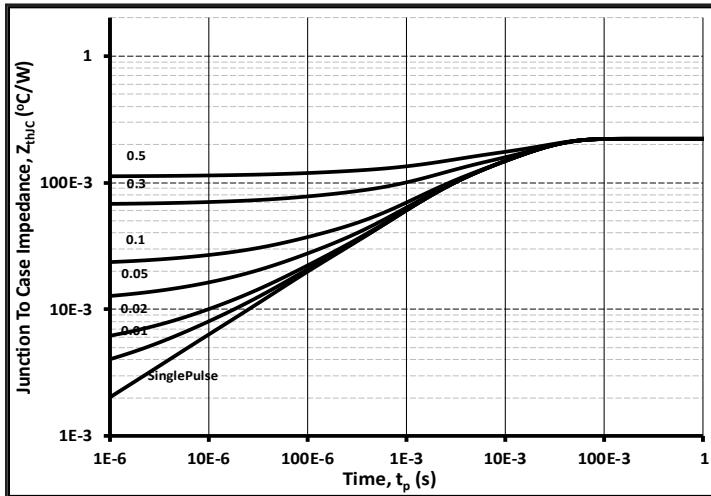


Figure 21. Transient Thermal Impedance
(Junction - Case)

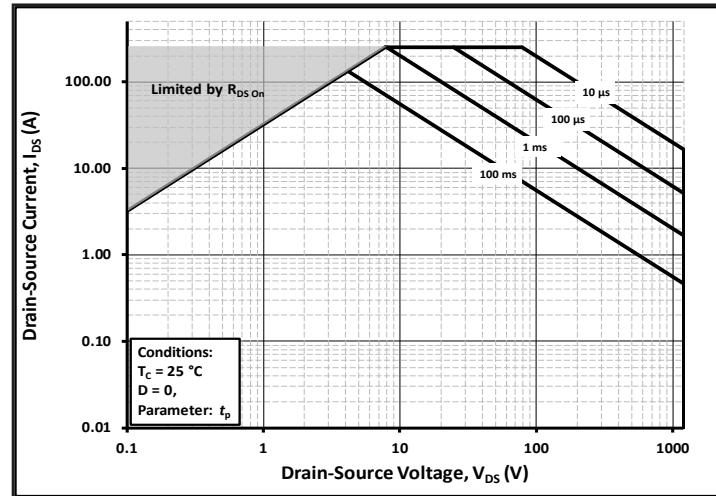


Figure 22. Safe Operating Area

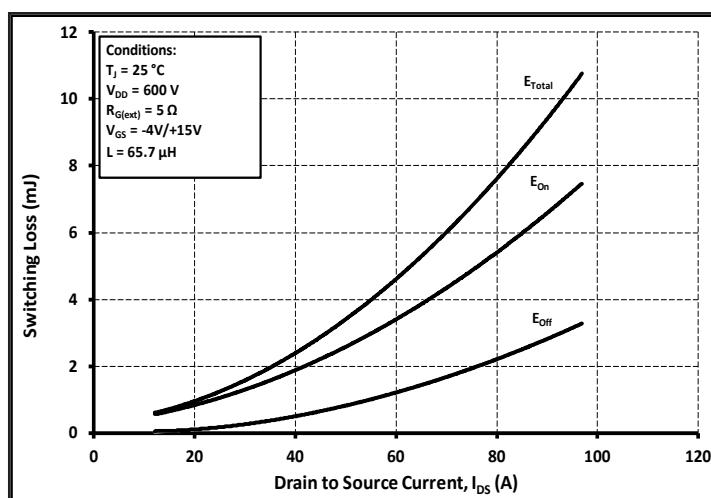


Figure 23. Clamped Inductive Switching Energy vs.
Drain Current ($V_{DD} = 600V$)

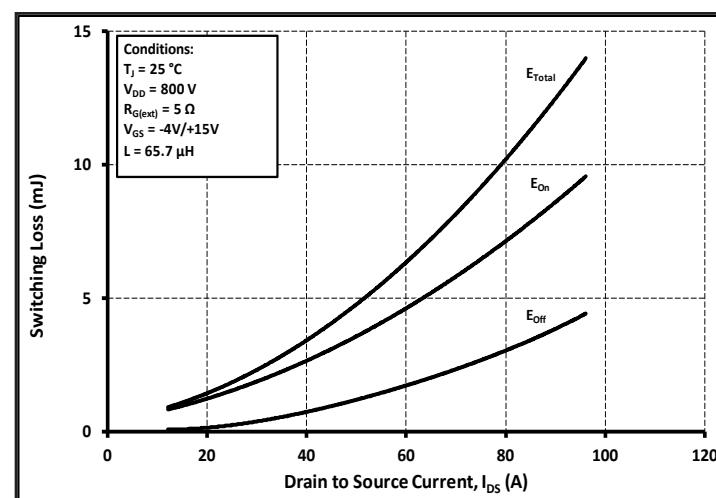


Figure 24. Clamped Inductive Switching Energy vs.
Drain Current ($V_{DD} = 800V$)

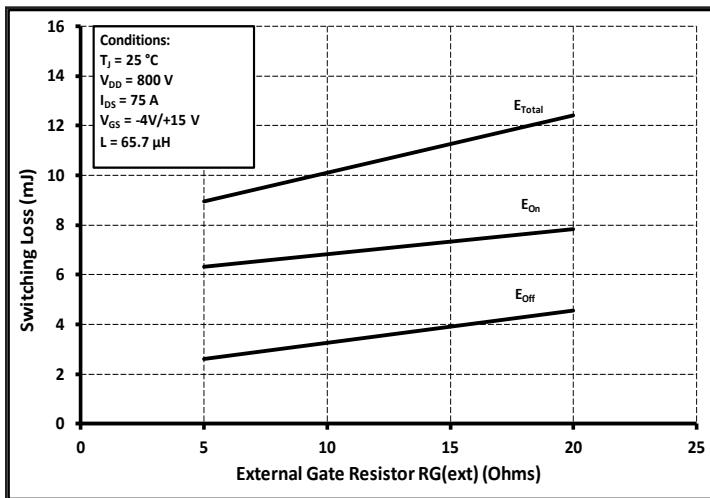
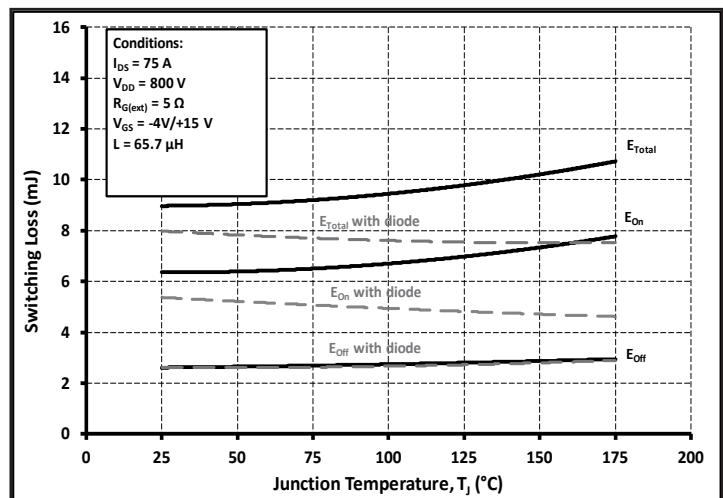

 Figure 25. Clamped Inductive Switching Energy vs. $R_{G(\text{ext})}$


Figure 26. Clamped Inductive Switching Energy vs. Temperature

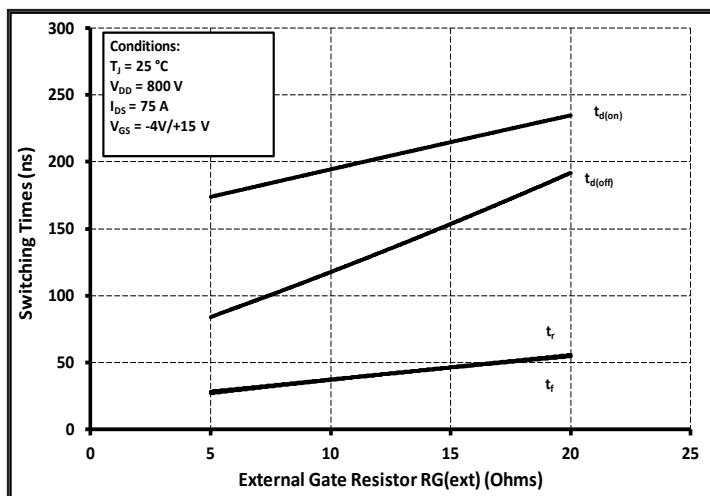
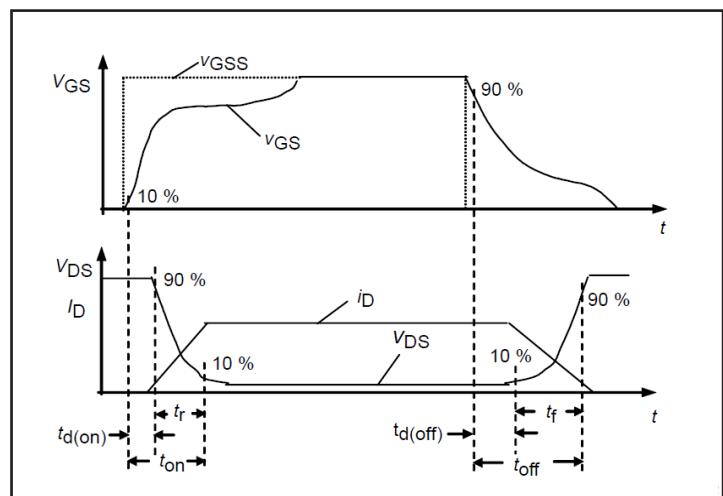

 Figure 27. Switching Times vs. $R_{G(\text{ext})}$


Figure 28. Switching Times Definition

Test Circuit Schematic

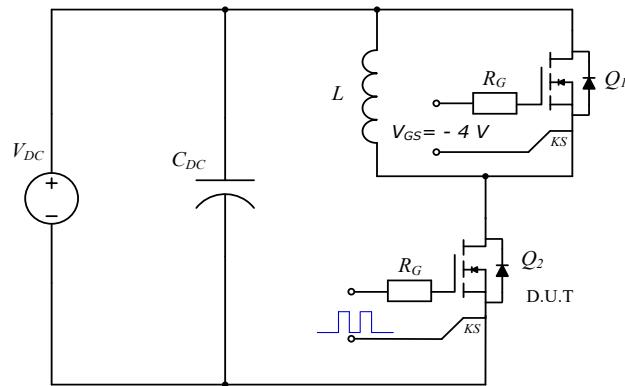
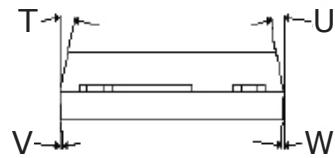
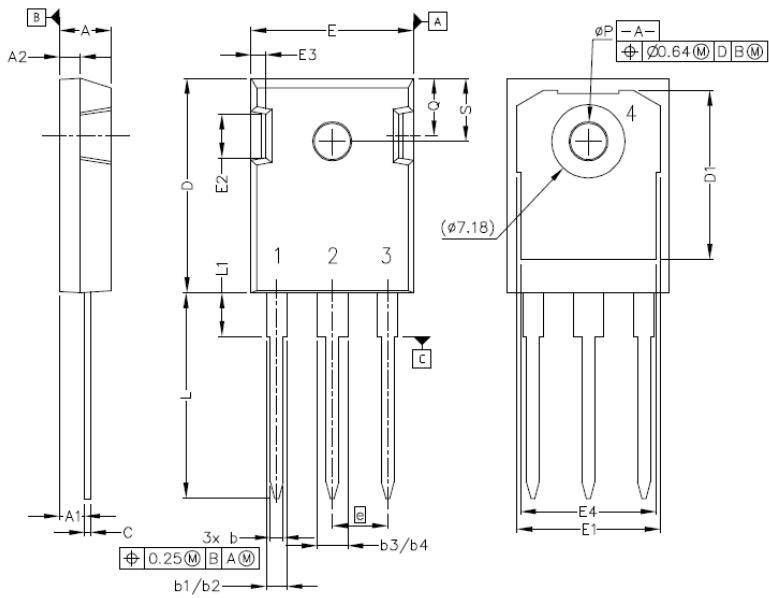


Figure 29. Clamped Inductive Switching Waveform Test Circuit

Note (3): Turn-off and Turn-on switching energy and timing values measured using SiC MOSFET Body Diode as shown above.

Package Dimensions

Package TO-247-3

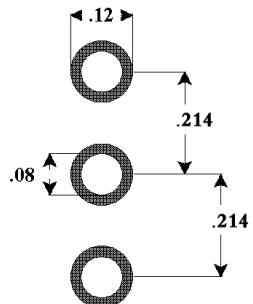


Pinout Information:

- Pin 1 = Gate
- Pin 2, 4 = Drain
- Pin 3 = Source

POS	Inches		Millimeters	
	Min	Max	Min	Max
A	.190	.205	4.83	5.21
A1	.090	.100	2.29	2.54
A2	.075	.085	1.91	2.16
b	.042	.052	1.07	1.33
b1	.075	.095	1.91	2.41
b2	.075	.085	1.91	2.16
b3	.113	.133	2.87	3.38
b4	.113	.123	2.87	3.13
c	.022	.027	0.55	0.68
D	.819	.831	20.80	21.10
D1	.640	.695	16.25	17.65
D2	.037	.049	0.95	1.25
E	.620	.635	15.75	16.13
E1	.516	.557	13.10	14.15
E2	.145	.201	3.68	5.10
E3	.039	.075	1.00	1.90
E4	.487	.529	12.38	13.43
e	.214 BSC		5.44 BSC	
N	3		3	
L	.780	.800	19.81	20.32
L1	.161	.173	4.10	4.40
ØP	.138	.144	3.51	3.65
Q	.216	.236	5.49	6.00
S	.238	.248	6.04	6.30
T	9°	11°	9°	11°
U	9°	11°	9°	11°
V	2°	8°	2°	8°
W	2°	8°	2°	8°

Recommended Solder Pad Layout



TO-247-3